Date: December 12, 2006



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Soichi Kobayashi et al.

Application No.: 10/632,928

Filed: August 4, 2003

For: SEMICONDUCTOR INTEGRATED

CIRCUIT CAPABLE OF TESTING WITH SMALL SCALE CIRCUIT

CONFIGURATION

MAIL STOP AF

Group Art Unit: 2138

Examiner: SAQIB JAVAID

SIDDIQUI

Confirmation No.: 4942

RESPONSE UNDER 37 C.F.R. §1.116

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

This Response responds to the Office Action dated July 14, 2006 (Paper No. 20060708). Attached to this Response is a petition for extension of time for a two month period.